

# Questions

- What are You interested in, for analog FA ? Is the issue success *per se*, or also through-put time ( with 100% (or 95 %) success being a matter of course ?
- We are discussing several methods to improve localization to the block- or sub block level : Analog Emiscope, or Laser Modulation Mapping, or Variation mapping ( as well as 'conventional' photoemission ). But some of these require application from the back side.

How are You following this up ?

Can you always go to Microprobing, or is 'conventional' in circuit probing ( with front side access, when the sample is already prepared for back side) needed as an intermediate step ?

How to fit these methods into a reliable FA 'flow' ? Any ideas?

- To what extent is the designing in of probe pad locations in analog blocks, an answer to the through-put time issue of analog FA On devices with > 3 metals ?

What are your experiences ?